

# CPW2-0650-S008B-Silicon Carbide Schottky Diode Chip

Z-REC<sup>TM</sup> RECTIFIER

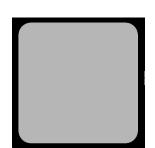
 $V_{RRM} = 650 \text{ V}$ 

 $\mathbf{I}_{\mathsf{F}(\mathsf{AVG})} = 8 \; \mathsf{A}$ 

= 21 nC

### **Features**

- 650-Volt Schottky Rectifier
- Zero Reverse Recovery
- Zero Forward Recovery
- High-Frequency Operation
- Temperature-Independent Switching Behavior
- Extremely Fast Switching
- Positive Temperature Coefficient on V<sub>F</sub>



**Chip Outline** 

Part Number	Anode	Cathode	Package	Marking
CPW2-0650-S008B	Al	Ni/Ag	Sawn on Foil	Wafer # on Foil

# **Maximum Ratings**

Symbol	Parameter	Value	Unit	Test Conditions	Note
V <sub>RRM</sub>	Repetitive Peak Reverse Voltage	650	V		
V <sub>RSM</sub>	Surge Peak Reverse Voltage	650	V		
V <sub>DC</sub>	DC Blocking Voltage	650	V		
$I_{\text{F(AVG)}}$	Average Forward Current	8	А	T <sub>j</sub> =175°C	
I <sub>FRM</sub>	Repetitive Peak Forward Surge Current	57	А	$T_c=25$ °C, $t_p=10$ ms, Half Sine Wave, D=0.3	1
$I_{FSM}$	Non-Repetitive Peak Forward Surge Current	220	А	T <sub>c</sub> =25°C, t <sub>p</sub> =10 μs, Pulse	1
T <sub>J</sub> , T <sub>stg</sub>	Operating Junction and Storage Temperature	-55 to +175	°C		



## **Electrical Characteristics**

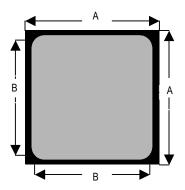
Symbol	Parameter	Тур.	Max.	Unit	Test Conditions	Note
V <sub>F</sub>	Forward Voltage	1.6 1.9	1.8 2.4	V	$I_F = 8 \text{ A } T_J = 25^{\circ}\text{C}$ $I_F = 8 \text{ A } T_J = 175^{\circ}\text{C}$	
I <sub>R</sub>	Reverse Current	12 24	60 220	μΑ	$V_R = 650 \text{ V } T_J = 25^{\circ}\text{C}$ $V_R = 650 \text{ V } T_J = 175^{\circ}\text{C}$	
Q <sub>c</sub>	Total Capacitive Charge	21		nC	$V_R = 650 \text{ V, } I_F = 8 \text{ A}$ $di/dt = 500 \text{ A/}\mu\text{s}$ $T_J = 25^{\circ}\text{C}$	
С	Total Capacitance	441 39 33		pF	$V_R = 0 \text{ V}, T_J = 25^{\circ}\text{C}, f = 1 \text{ MHz}$ $V_R = 200 \text{ V}, T_J = 25^{\circ}\text{C}, f = 1 \text{ MHz}$ $V_R = 400 \text{ V}, T_J = 25^{\circ}\text{C}, f = 1 \text{ MHz}$	

Note: 1. Assumes  $\theta JC$  Thermal Resistance of 1.5°C/W or less

Mechanical Parameters						
Parameter	Тур.	Unit				
Die Size	1.77 x 1.77	mm				
Anode Pad Size	1.45 x 1.45	mm				
Anode Pad Opening	1.38 x 1.38	mm				
Thickness	377 ± 10%	μm				
Wafer Size	100	mm				
Anode Metalization (AI)	4	μm				
Cathode Metalization (Ni/Ag)	1.8	μm				
Frontside Passivation	Polyimide					



# **Chip Dimensions**



symbol	dimension				
	mm	inch			
Α	1.77	0.070			
В	1.45	0.057			

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The die-on-tape method of delivering these SiC die may be considered a means of temporary storage only. Due to an increase in adhesion over time, die stored for an extended period may affix too strongly to the tape. These die should be stored in a temperature-controlled nitrogen dry box soon after receipt. Cree will further recommend that all die be removed from tape to a waffle pack, to a similar storage medium, or used in production within 2 – 3 weeks of delivery to assure 100% release of all die without issues.